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**The Microanalysis Society invites you to the EBSD 2020 topical conference:**

The MAS EBSD topical conference series is dedicated to the characterization of crystalline materials using electron backscatter diffraction (EBSD) on the scanning electron microscope. EBSD 2020 will bring together EBSD developers and users of all abilities—across the materials and Earth sciences—for a three day meeting, including one full day of beginner- and advanced-level tutorials.

**Beginner Tutorials:**

History and intro to EBSD  
EBSD technology and data acquisition  
Sample preparation  
Applications and case studies

**Advanced Tutorials:**

Cross-correlation EBSD  
Transmission Kikuchi Diffraction  
Crystal plasticity modeling

**Keynote Speakers:**

Kenneth Vecchio, UCSD—Machine learning and phase identification  
Philip Noell, LANL—In situ deformation and EBSD  
Arun Bhattacharya, ORNL—TKD on nuclear structural materials  
Elisabetta Mariani, Liverpool—Decoding deformation in Earth materials  
David Wallis, Utrecht—HR-EBSD on geological minerals  
Omero Orlandini, UT Austin—Brittle anomalies in the ductile lower crust

**Registration fees:**

\$275—Regular  
\$125—Student\*

\* Student travel support may be available

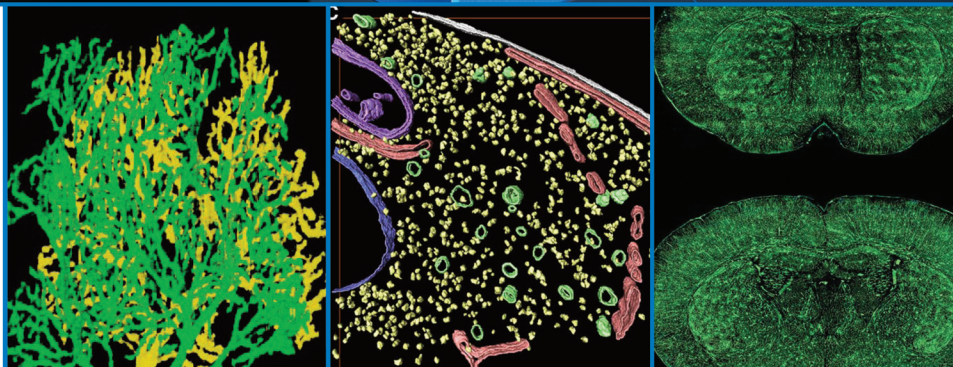
**NOVEMBER 1st—REGISTRATION OPENS**  
**MARCH 1st—REGISTRATION/ABSTRACT SUBMISSION DEADLINE**

<https://the-mas.org/events/topical-conferences/ebsd-2020/>

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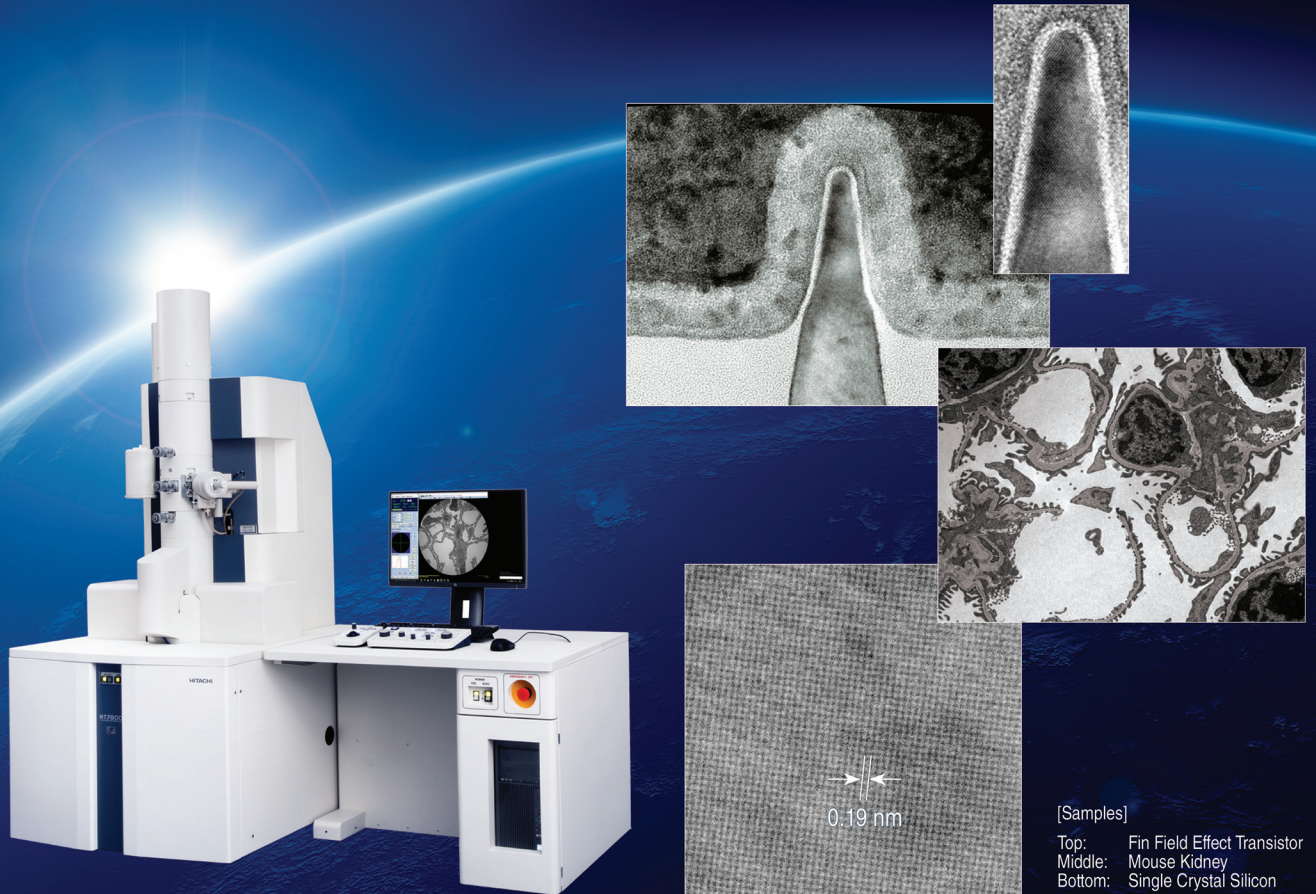
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